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Huang Yanyan; Gao Na; Yu Ming; Zhao Xiaoan;  
Intelligent Information Technology Application, 2008. IITA '08. Second International Symposium  
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Yang Musheng; Zhang Yu; Wang Huilin;  
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**3. Visual quality recognition of nonwovens based on wavelet transform and LVQ neural net**

Jianli Liu; Baoqi Zuo; Vroman, P.; Rabenasolo, B.; Xianyi Zeng;  
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Bo Cui; Haiying Liu; Tongze Xue;  
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**5. Automatic image processing filter generation for visual defects classification system**

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Hata, S.; Tanaka, T.; Iga, T.; Nakamura, T.;  
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**10. The development of an artificial neural network embedded automated inspection quality**

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**11. Graphics file generation for a computer-aided manual work station in the electronics man  
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Hidde, A.R.; Rath, H.;  
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